

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10509337	AIKAWA ET AL.
	Examiner	Art Unit
	RICHARD CHAN	2618

SEARCHED

Class	Subclass	Date	Examiner
455	101, 103, 105, 127.1,	6/20/08	RC
375	144, 146	6/20/08	RC

SEARCH NOTES

Search Notes	Date	Examiner

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner